

Docket No.: W&B-INF-1850

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : CARSTEN OHLHOFF ET AL.  
Filed : CONCURRENTLY HEREWITH  
Title : TEST CIRCUIT AND METHOD FOR TESTING AN INTEGRATED  
MEMORY CIRCUIT

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In accordance with 37 C.F.R. 1.98 copies of the following patents and/or publications are submitted herewith:

U.S. Patent No. 6,539,505 B1 (Dähn), dated March 25, 2003, and corresponding German Published Non-Prosecuted Patent Application DE 199 22 786 A1 (Dähn), dated December 7, 2000.

Respectfully submitted,

  
For Applicants

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Date: July 3, 2003

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/nt/kf

<b>FORM PTO-1449 (SUBSTITUTE)</b>  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  <b>INFORMATION DISCLOSURE          STATEMENT BY APPLICANT</b> (37 CFR 1.98(b))				Attorney Docket No.: W&B-INF-1850 Appl. No.:  <hr/> Applicant: CARSTEN OHLHOFF ET AL.  <hr/> Filing Date: July 3, 2003 Group Art Unit:			
EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
	A	6,539,505 B1	3/25/03	Dähn			
	B						
	C						
	D						
	E						
	F						
	G						
	H						
	I						
<b>FOREIGN PATENT DOCUMENT</b>							
		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES   NO
	J	199 22 786 A1	12/7/00	Germany			
	K						
	L						
	M						
	N						
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
<b>EXAMINER</b>				<b>DATE CONSIDERED</b>			